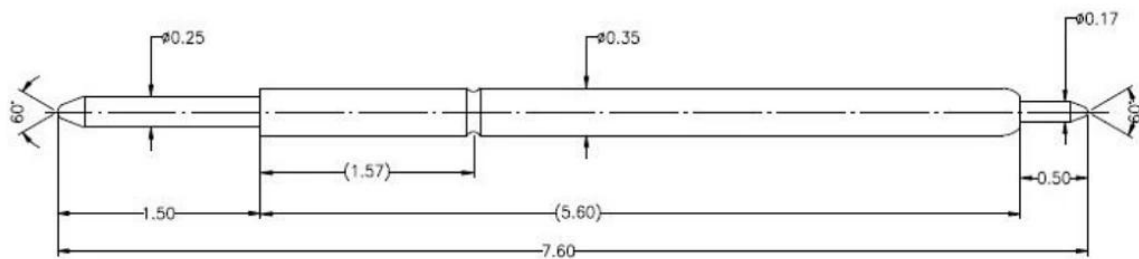


BGA

	ENG
	SF035B760B30
	B
	SWP
	30 ±20 @ 0.65mm
	50m
	1A
	100
	2-15





Probe Specifications (探针各项参数)	Pitch (中心距)	Pointing Accuracy (直线性/角度度)	Cycle Time (循环寿命)	Contact Resistance (接触电阻)	Current Rating-Continuous Time (额定电流-持续时间)	Operating Temperature (使用温度)	Bandwidth (频宽)
/	/	±0.05mm	>80,000次	120mohm max	/	-40~80℃	N/A

Name (名称)		Spring Probe				SF035B760B30				
Initial Travel (初始行程)	Travel(mm) (行程)	Spring Force (弹力)	Part (零件)	Material (材质)	Finish (表面处理)	Size	A4	Design	Check	Approve
recommended Travel (推荐行程)	0.65	30	Spring (弹簧)	Music Wire	Gold Plated	Scale	6:1	刘尚尚		
Full Travel (全行程)	0.8	/	Barrel (针管)	Phosphor Copper	Gold Plated	Unit	mm			
			Left Plunger (左针头)	Becu	Gold Plated	Rev	A0	胜峰科技 SFENG PROBE		
			Right Plunger (右针头)	Becu	Gold Plated	Sheet	1/1			

□□□□□□

- 1.we have 30 years experience in probe pin and have ourself factory.
- 2.we provide free sample and have a testing department.
- 3.we could manufacture products as your request.
- 4.we guarantee best price and good service.

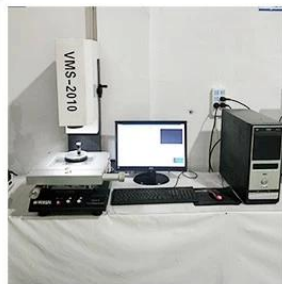
□□□□□□□□

Spring loaded pin (single) for PCB, ICT, FCT testing etc;
Pogo pin (connector) to establish connection between two printed circuit boards for charging, locating, Battery, Semiconductor & Interconnect applications;
Double ended probe for BGA and Semiconductor testing;
Universal pin without spring, coating pin, LM pin with QZ and VZ series;
High current probe, Switch probe, Capacitance needle;
Terminal & receptacle /socket;
Other related electronic components, 30# OK wire, Jig locks, POM, Iron hinge etc

□□□□□



1. Agilent current testing



2. Quadratic element



3. Load Curve Meter



4. Bond Test



5. Life Fatigue Test



6. Microscope

□□

Standard products will be delivered out within 3 days. Customized products will be sent out within 15 days.

